Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	"6834213",pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:03
L2	1	"6407396".pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:05
L3	1	"6773931".pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:07
L4	1	"6740534".pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:09
L5	1	"6563300".pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF.	2005/05/10:10:10
L6	1	"6303395".pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:12
L7	1	"5526293".pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:14
L8	1901	700/108-110,121.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:14
L9	124	18 and routing	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:14
L10	81	I9 and semiconductor	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:14
L11	65	I10 not (advanced.as.)	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10:10:17
L12	14	l10 and routing with wafer	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:34
L13	37	110 and routing same wafer	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10:10:34
L14	44	I10 and rout\$3 same wafer	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 10:34
L15	23	J10: and: rout\$3 with: wafer	US-PGPUB; USPAT; EPO; JPO	OR	OF	2005/05/10:10:34
S1	1186	700/121.cds.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/05/10 09:46
S2	6	S1 and hot adj lot\$2:	US-PGPUB; USPAT; EPO; JPO	OR	OF	2005/03/08 17:27
S 3	1	"6584369".pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/08 17:24
S4:	20	hot adj lot\$1 and (semiconductor or wafer) and tool	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 09:54

S5 .	20	S4 notl2	US-PGPUB; USPAT;	OR	OFF	2005/03/08 17:27
S6	16	S4 not S2	EPO; JPO US-PGPUB;	OR	OFF	2005/03/08 17:29
67		CC and maked an	EPO; JPO	00	000	2005/02/09 17-20
S7	6	S6 and metrology	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/08 17:29
58	10	hot adj lot\$1 and metrology	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/08 17:32
S9	4	S8 not S7	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/08 17:32
S10	0	hot adj lot\$1 and critical adj dimension	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/08 17:32
S11	50	hot adj lot\$1	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/08 17:32
S12	43	S11 and (semiconductor or wafer or substrate)	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/08 17:33
S13	7	S11 and frequency	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/08 17:33
514	20	S11 and "700"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/08 17:44
S15	1	"6834213".pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/08 17:44
S16	0	("6834213").URPN.	USPAT	OR	OFF	2005/03/08 17:44
S17	. 3	("5801965" "6584368" "6587744").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/03/08 17:51
S18	22	high adj priority near3 lots and (semiconductor or wafer or substrate)	US-PGPUB; USPAT; USOCR	OR	OFF	2005/03/08 17:51
519	11	(US-20020107599-\$ or US-20030171972-\$ or US-20040107020-\$ or US-20040151562-\$ or US-20040260419-\$).did. or (US-5586021-\$ or US-5751580-\$ or US-6584368-\$ or US-6584369-\$ or US-6587744-\$ or US-6594536-\$).did.	US-PGPUB; USPAT	OR	OFF	2005/03/09 09:54
S20	1	S19 and frequency	US-PGPUB; USPAT; EPO; JPO	OR	OFF.	2005/03/09 09:54
S21	310	(semiconductor or wafer) and tool and frequency near5 (metrology or feedback)	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 09:55
S22	13	S21 and "700"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	OFF.	2005/03/09 09:57
S23	2	700/121.ccls. and frequency near3 metrology	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 10:00
S24	10	("6192103" "6248602" "6368883" "6405096" "6460002" "6528331" "6535774" "6589800" "6607926" "6622061"). PN:	US-PGPUB; USPAT; USOCR	OR	OFF.	2005/03/09 09:58
S25	1	("6766214").URPN.	USPAT	OR	OFF	2005/03/09 09:59

S26	27	("20020135781" "20030204348" "20040121495" "5867276" "5877860" "5880838" "5956692" "6051348" "6055463" "6081334" "6115643" "6141107" "6223098" "6245584" "6319884" "6383888" "6423977" "6433878" "6445969" "6479200" "6529282" "6597447" "6643557" "6650955" "6721939" "6742168" "6766214").PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2005/03/09 09:59
S27	22	.700/121:ccls: and (sampling adj frequency or sampling adj rate)	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 10:01
S28	2117	700/121,100,101,99,104,108.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 10:07
S29	198	S28 and metrology	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 10:07
530	5	S29 and (priority or hot) adj lot	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 10:08
531	1977	.705/7,9.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 10:08
S32	5	S31 and (priority or hot) adj lot	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 10:08
S33	12	(US-20020107599-\$ or US-20030171972-\$ or US-20040107020-\$ or US-20040151562-\$ or US-20040260419-\$ or US-20020193899-\$).did: or (US-5586021-\$ or US-5751580-\$ or US-6584368-\$ or US-6584369-\$ or US-6587744-\$ or US-6594536-\$).did:	US-PGPUB; USPAT	OR	OFF	2005/03/09 12:51
S34	4	S33 and test	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 15:53
S35	2	S33 and test adj wafer	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 13:21
S36	6	S33 and cycle adj time	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 13:22
S37	0	S33 and noben	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 13:22
S38	1186	700/121.ccls.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 13:22
S39	0	S38 and noben	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 13:23
S40	0	S38 and mini adj batch adj manufacturing	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 13:23
S41	0	mini adj batch adj manufacturing	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 13:23
542	1	"6587742".pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 16:06
S43	1	"6775593":pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF.	2005/03/09:16:07
S44	1	"6757589".pn.	US-PGPUB; USPAT; EPO; JPO	OR	OFF	2005/03/09 16:07